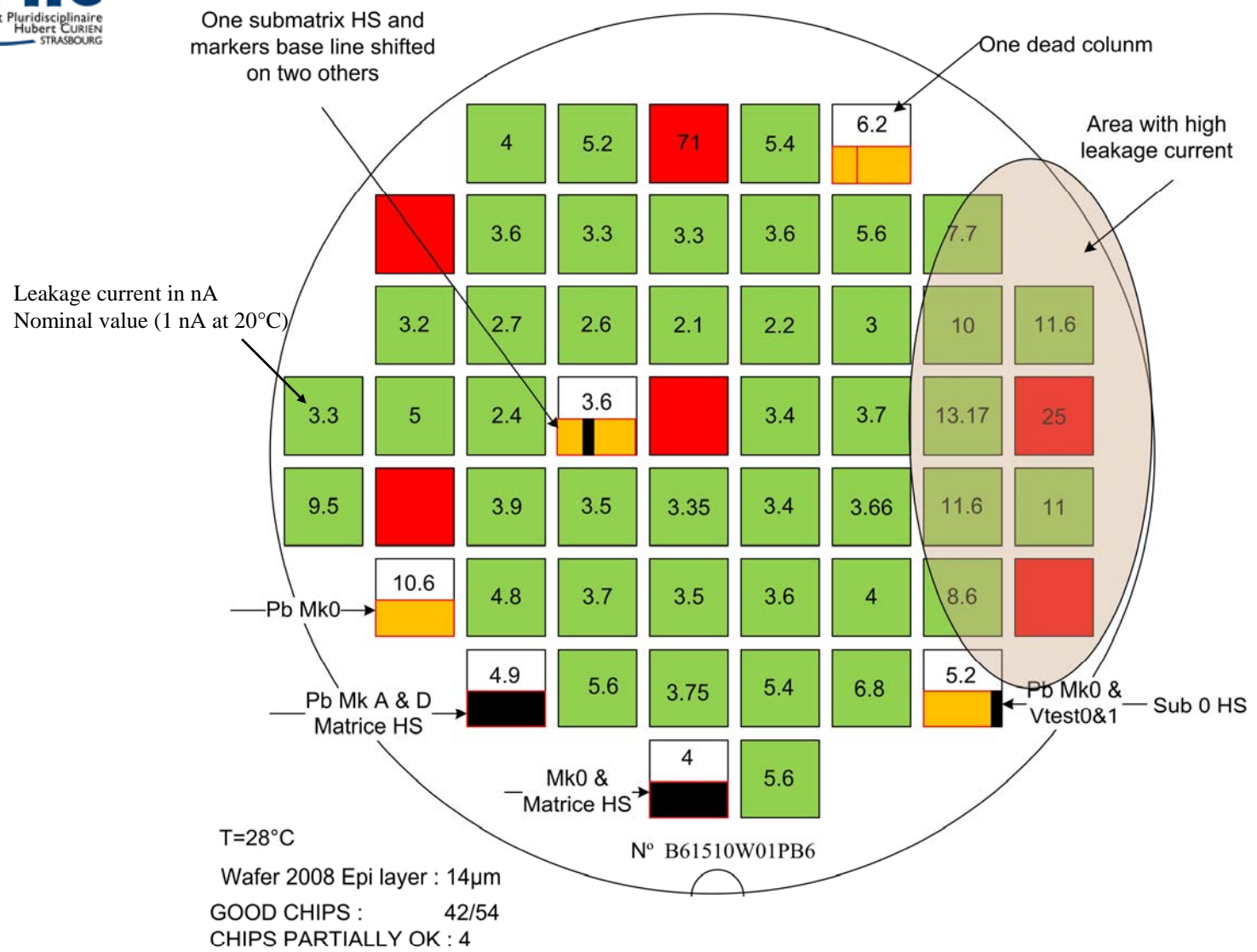




Probe test on the 2008 wafer batch

- 6 new wafers received last week (18th of June) with epitaxial layer of 14 μm
- 3 wafers probe tested up to now:
 - Measure leakage current, analog and digital consumption
 - JTAG loading
 - Test digital markers
 - Acquisition of two frames (in the dark and with light) to evaluate the dead pixel and to check the sensibility to light of the pixels



Matrix in red are with high leakage current (low response pixel)
but the JTAG, digital Marker and others consumption are OK



Conclusion

- The results on the two other wafers are similar
- The Yield is around 80-85%
- No more unconnected pixel area discover on the 162 chips tested. (problem solved)

- The test of the 3 remaining wafers will be done in the next days and the results will be communicated as soon as possible

- The wafer N°1 is ready to be sent to LBL.